

	1	Mini (Lons	stan	t	Ten	np	er	ature	· (Chamberer				
1. Product model number	WHW-25L-S														
Model naming method		Mode	<u>.</u>	W H W	-	25 L	-	4T	S	-	5V10mA 160CH	-	220 V	-	В
		Characteristic		1		2		3	4		(5)		6		7
			1	Constant temperature test box series											
			2	Nominal volume: 25L (other digital analogy)											
			3	4T:	4T: 4 temperature zones (not indicated by the single temperature zone)										
		Symbol meaning	4	Refrigeration mode: S represents the semiconductor refrigeration $(\text{temperature range: } 15^{\circ}\text{C -}60^{\circ}\text{C})$ Compressor refrigeration does not indicate (temperature range: 0°C - 60°C)											
			5	5V10mA 160CH: Power supply equipment specifications and number of channels, but not omitted by default											
			6	220V: Equipment voltage 220V (default 220V omitted not indicated, other voltages by analogy)											
			7	B: Product iteration update version number, then A, B, C, Default A											
2. Product	Cons	tant tampar	does not indicate												
application	Constant temperature test of buckle cell and new energy small soft package polymer cell (millipere level)														
3. Limit the sample	This test equipment is prohibited by: Test or storage of samples of inflammable, explosive and volatile substances Test or storage of test samples of corrosive substances Test or storage of samples of strong electromagnetic emission sources Test and storage of test samples of radioactive substances Test and storage of test samples of highly toxic substances Testing or storage of tests or specimens that may produce such substances or objects														
4. Volume, size a	nd we	eight													
4.1 Nominal															
content	25L														
4.2 Inner box	W280mm × D250mm × H330mm														
4.3 Overall dimensions	W360mm × D450mm × H500mm														

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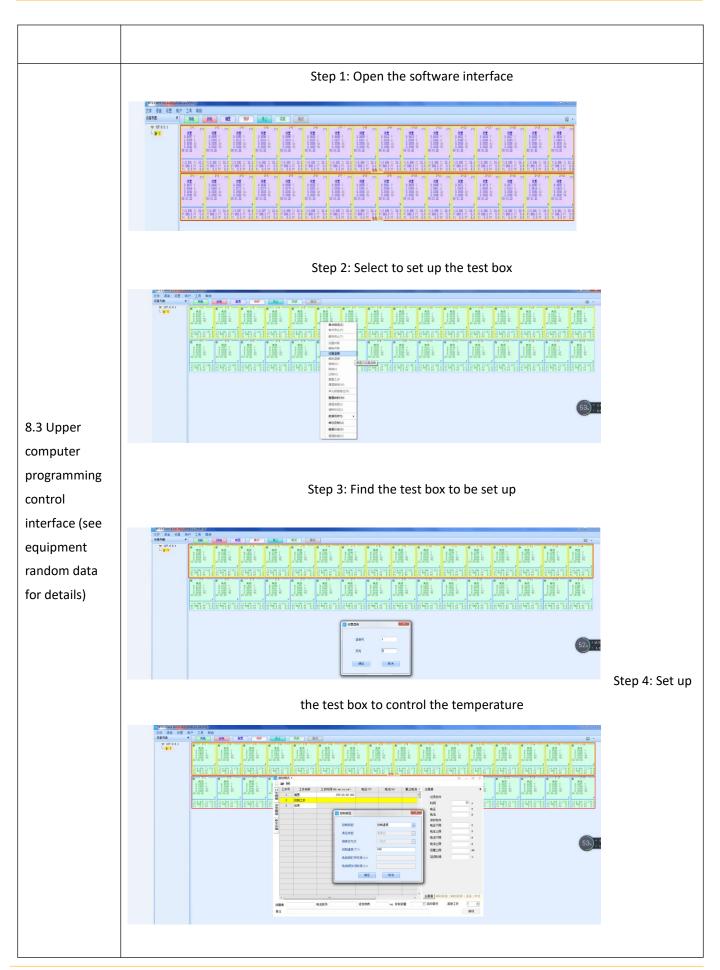


4.4 Net weight								
of the	About 40kg							
equipment								
5. Performance								
5.1 Test the	Ambient temperature is + 25 $^{\circ}$ C, relative humidity is 85%, with no sample in the test box (no							
environmental								
conditions								
5.2								
Temperature	15~60 ℃							
range								
5.3								
Temperature	1°C (a minulant to 1 0 5°C mills as local at labels to a second							
fluctuation	${f 1}^{\circ}{\Bbb C}$ (equivalent to ${f \pm}$ 0.5 ${\Bbb C}$, with no load and stable temperature)							
degree								
5.4								
Temperature	± 2.0 °C (when no load and temperature is stable)							
deviation								
5.5 Heating-up	25°C×60°C×50 min (no load outros montinocuito)							
time	25℃~60℃ ≤50 min (no load, average nonlinearity)							
5.6 Cooling	25°C~15°C ≤60 min (no load, average nonlinearity)							
down time	25 C 15 C 500 IIIII (IIO IOAU, AVEIAGE NOMIMEANLY)							
6. Structural cha	racteristics							
6.1 Thermal	Outer wall materials high quality cold relied steel plate, surface enroy plactic and point treatment							
insulation and	Outer wall material: high quality cold-rolled steel plate, surface spray plastic and paint treatment							
envelope	Inner wall material: stainless steel plate SUS304							
structure	Box body insulation material: polyurethane foam							
6.2 Air								
conditioning	Axial flow fan, semiconductor refrigeration (heating) module							
channel								
6.3 Standard configuration of the test box	Box door: hollow tempered glass + frame							
	Lead hole (with soft plug): φ 50mm / 1 (at the back of the box) Cell tray: electric insulation, cell tray 2 layers, load-bearing (all cloth): 2kg							
	Lighting: LED lighting lamp							
	6.4 The Control	Touch-type control button						
Panel								

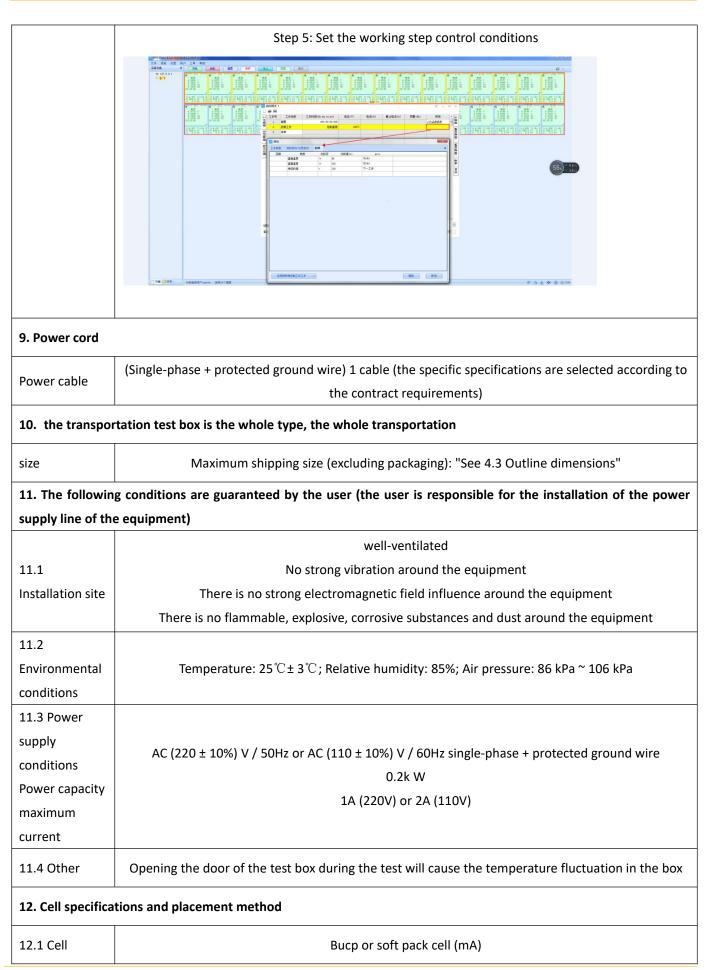


6.5 Air	
conditioning	Semiconductor refrigeration (heating) module
unit	
7. Electrical cont	crol system
7.1 controller	LED digital display + touch key type controller
7.2 Setting mode	Touch key type
7.3 Control	Forced circulation ventilation. The control system controls the output of the semiconductor
mode	refrigeration (heating) module through the PID automatic operation output result according to the
	set temperature value, so as to achieve a dynamic balance
7.4	
Communicatio n mode	The Ethernet standard interface
8. Interconnection	on with the battery cell testing equipment
	BTS upper computer, cell testing equipment and test box pass Channel lines, and data communication lines to achieve hardware interconnection
	channel lines, and data communication lines to achieve hardware interconnection
8.1 Hardware	
connection of	
the equipment	
	NEWARE Out of the state of the
	MES生产管理系统 数据库服务器 TCP/IP WiFi TCP/IP TCP/IP
8.2 Schematic	App で TCP/IP TCP/IP TCP/IP
diagram of the	BIS上位机系统
network	TO BUR
	TCP/IP TCP/IP TCP/IP TCP/IP











specifications	
12.2 Cells placement mode	Second floor placement (up to 8 buckle cells can be placed on each floor)
12.3 Cell tray form and cell fixing mode (cell tray can be customized as needed) Cell tray using electric,	
insulated electric wood quality	Button cell